

<b>Notice of References Cited</b>	Application/Control No. 10/078,317	Applicant(s)/Patent Under Reexamination LIU ET AL.	
	Examiner Alonzo Chambliss	Art Unit 2827	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,391,915	02-1995	Mukai et al.	257/643
	B	US-5,093,713	03-1992	Sawaya, Hiromichi	257/724
	C	US-6,215,177	04-2001	Corisis et al.	257/666
	D	US-6,486,535	11-2002	Liu, Sheng Tsung	257/666
	E	US-5,243,496	09-1993	Mermet-Guyennet, Michel	361/748
	F	US-5,089,878	02-1992	Lee, Jaesup N.	257/664
	G	US-5,198,964	03-1993	Ito et al.	361/717
	H	US-5,532,910	07-1996	Suzuki et al.	361/813
	I	US-5,281,846	01-1994	Kaiser, Ulrich	257/528
	J	US-6,320,757	11-2001	Liu, Sheng-Tsung	361/760
	K	US-6,429,536	08-2002	Liu et al.	257/786
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 59054249 A	03-1984	Japan	WAKABAYASHI et al.	H01L 23/12
	O	JP 59072757 A	04-1984	Japan	WAKABAYASHI et al.	H01L 25/02
	P	JP 05082697 A	04-1993	Japan	UENOYAMA et al.	H01L 23/50
	Q	JP 02007459 A	01-1990	Japan	NAKADA, TAKAAKI	H01L 25/00
	R	JP 59 054254 A	03-1984	Japan	Minoru Toyoda	
	S	DE 4021872 A1	01-1992	Germany	WESTERKAMP, HUGO	H01F 15/10
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.